International Rectifier

IRF1018EPbF IRF1018ESPbF IRF1018ESLPbF

HEXFET® Power MOSFET

Applications

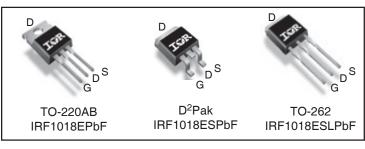
- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

G

V _{DSS}		60V
R _{DS(on)}	typ.	$7.1 m\Omega$
	max.	8.4m Ω
I _D		79A

Benefits

- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dl/dt Capability



G	D	S
Gate	Drain	Source

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	79		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	56	А	
DM	Pulsed Drain Current ①	315		
P _D @T _C = 25°C	Maximum Power Dissipation	110	W	
	Linear Derating Factor	0.76	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
dv/dt	Peak Diode Recovery ③	21	V/ns	
T _J	Operating Junction and	-55 to + 175	°C	
T _{STG}	Storage Temperature Range			
	Soldering Temperature, for 10 seconds	300		
	(1.6mm from case)			
	Mounting torque, 6-32 or M3 screw ®	10lb·in (1.1N·m)		

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ②	88	mJ
I _{AR}	Avalanche Current ①	47	Α
E _{AR}	Repetitive Avalanche Energy ®	11	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		1.32	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface , TO-220	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient, TO-220 ®		62	C/VV
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) , D²Pak ூ®		40	

Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.073		V/°C	Reference to 25°C, I _D = 5mA①
R _{DS(on)}	Static Drain-to-Source On-Resistance		7.1	8.4	mΩ	$V_{GS} = 10V, I_D = 47A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 100 \mu A$
I _{DSS}	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 60V$, $V_{GS} = 0V$
				250		$V_{DS} = 48V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$

Dynamic @ $T_1 = 25$ °C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	110			S	$V_{DS} = 50V, I_{D} = 47A$
Q_g	Total Gate Charge		46	69	nC	I _D = 47A
Q_{gs}	Gate-to-Source Charge		10			$V_{DS} = 30V$
Q_gd	Gate-to-Drain ("Miller") Charge		12			V _{GS} = 10V ⊕
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		34			$I_D = 47A$, $V_{DS} = 0V$, $V_{GS} = 10V$
R _{G(int)}	Internal Gate Resistance		0.73		Ω	
t _{d(on)}	Turn-On Delay Time		13		ns	$V_{DD} = 39V$
t _r	Rise Time		35	_		$I_D = 47A$
$t_{d(off)}$	Turn-Off Delay Time		55			$R_G = 10\Omega$
t _f	Fall Time		46			V _{GS} = 10V ④
C _{iss}	Input Capacitance		2290			$V_{GS} = 0V$
C _{oss}	Output Capacitance		270			$V_{DS} = 50V$
C _{rss}	Reverse Transfer Capacitance		130		рF	f = 1.0MHz
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related)@		390			V _{GS} = 0V, V _{DS} = 0V to 60V ©
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)®		630			$V_{GS} = 0V$, $V_{DS} = 0V$ to $60V$ \bigcirc

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			79	Α	MOSFET symbol
	(Body Diode)					showing the
I _{SM}	Pulsed Source Current			315		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 47A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		26	39	ns	$T_{J} = 25^{\circ}C$ $V_{R} = 51V$,
			31	47	Ī	$T_J = 125^{\circ}C$ $I_F = 47A$
Q _{rr}	Reverse Recovery Charge		24	36	nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s \oplus
			35	53		$T_J = 125^{\circ}C$
I _{RRM}	Reverse Recovery Current		1.8		Α	$T_J = 25^{\circ}C$
t _{on}	Forward Turn-On Time	Intrins	ntrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting T_J = 25°C, L = 0.08mH R_G = 25 Ω , I_{AS} = 47A, V_{GS} =10V. Part not recommended for use above this value.
- $\label{eq:loss_def} \ensuremath{\Im} \ I_{SD} \leq 47A, \ di/dt \leq 1668A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.

- $^{\circ}$ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- $^{\circ}$ C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- 9 This is only applied to TO-220

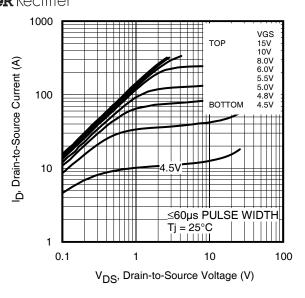


Fig 1. Typical Output Characteristics

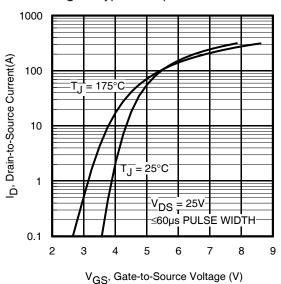


Fig 3. Typical Transfer Characteristics

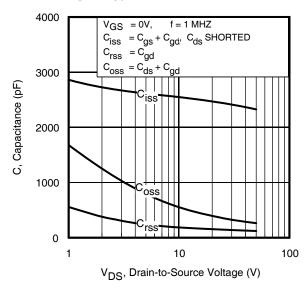


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

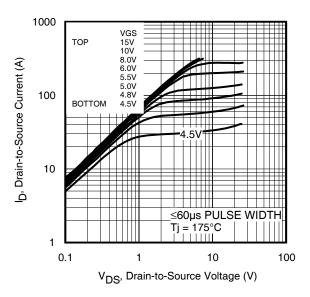


Fig 2. Typical Output Characteristics

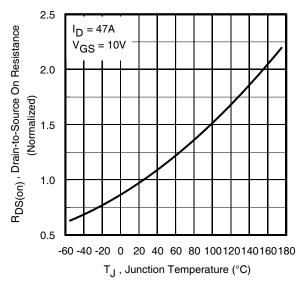


Fig 4. Normalized On-Resistance vs. Temperature

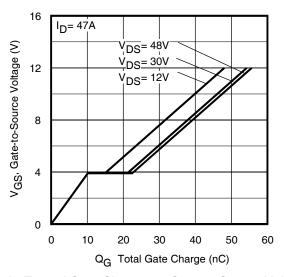


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

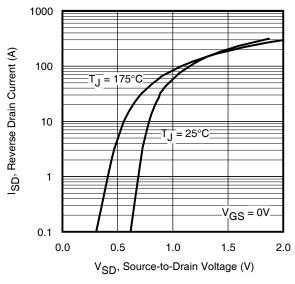


Fig 7. Typical Source-Drain Diode Forward Voltage

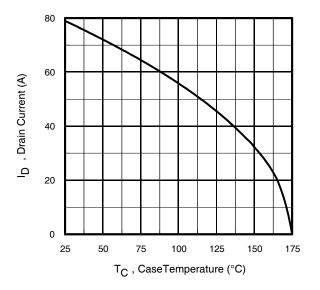


Fig 9. Maximum Drain Current vs. Case Temperature

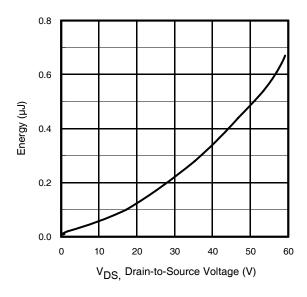


Fig 11. Typical C_{OSS} Stored Energy

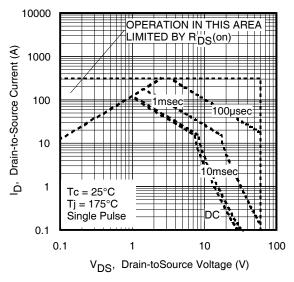


Fig 8. Maximum Safe Operating Area

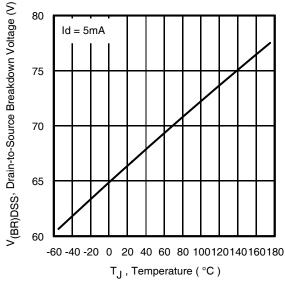


Fig 10. Drain-to-Source Breakdown Voltage

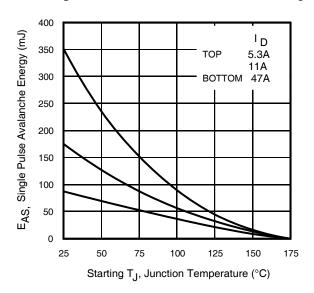


Fig 12. Maximum Avalanche Energy vs. DrainCurrent www.irf.com

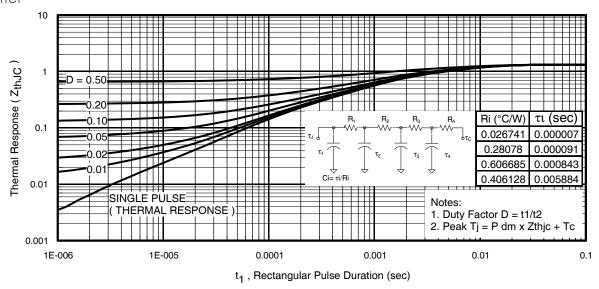


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

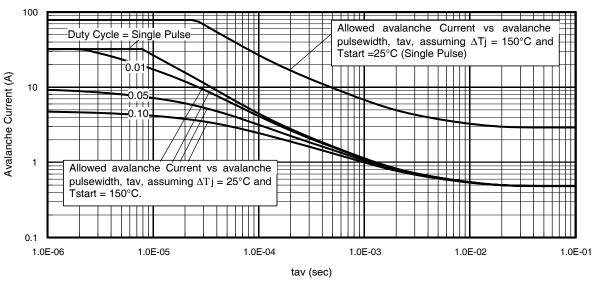


Fig 14. Typical Avalanche Current vs. Pulsewidth

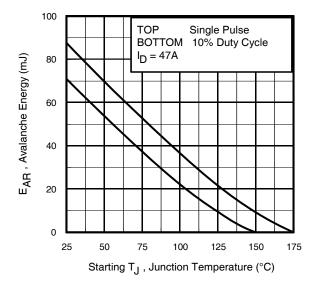


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot \text{BV} \cdot \text{I}_{av}) = \Delta \text{T/} \; Z_{thJC} \\ I_{av} &= 2\Delta \text{T/} \; [1.3 \cdot \text{BV} \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

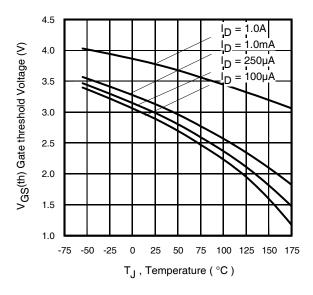


Fig 16. Threshold Voltage vs. Temperature

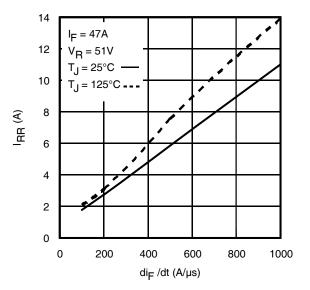


Fig. 18 - Typical Recovery Current vs. dif/dt

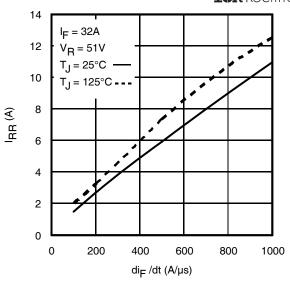


Fig. 17 - Typical Recovery Current vs. di_f/dt

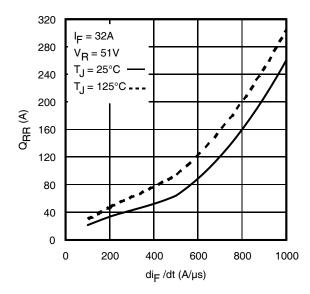


Fig. 19 - Typical Stored Charge vs. dif/dt

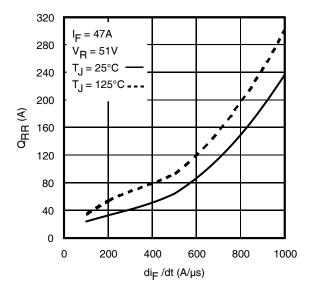


Fig. 20 - Typical Stored Charge vs. dif/dt

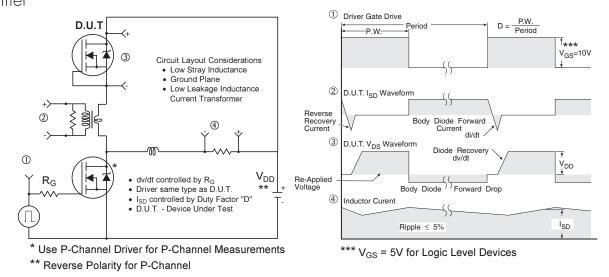


Fig 21. Diode Reverse Recovery Test Circuit for HEXFET® Power MOSFETs

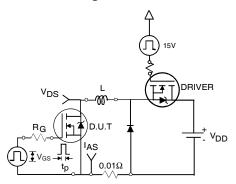


Fig 22a. Unclamped Inductive Test Circuit

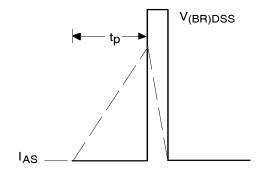


Fig 22b. Unclamped Inductive Waveforms

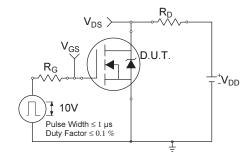


Fig 23a. Switching Time Test Circuit

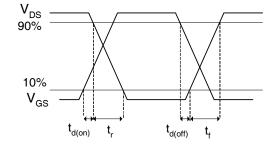


Fig 23b. Switching Time Waveforms

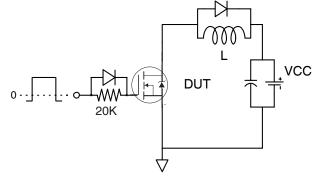


Fig 24a. Gate Charge Test Circuit

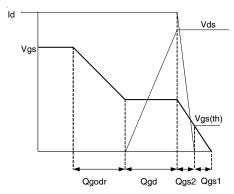
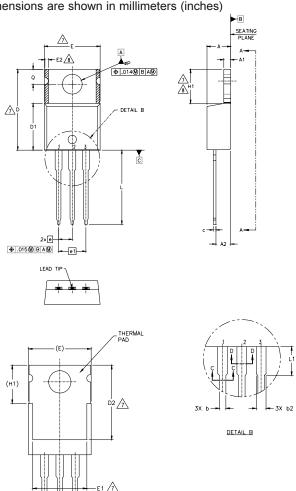


Fig 24b. Gate Charge Waveform

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
 DIMENSION D, D1 & E DO NOT INCLUDE MOLD FILASH. MOLD FLASH
 SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY. CONTROLLING DIMENSION: INCHES.

- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

		DIMEN	ISIONS		
SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
A	3.56	4.83	.140	.190	
A1	0.51	1.40	.020	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
ь1	0.38	0.97	.015	.038	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
e		BSC		BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
øΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS HEXFET 1.- GATE 2.- DRAIN 3.- SOURCE

IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

TO-220AB Part Marking Information

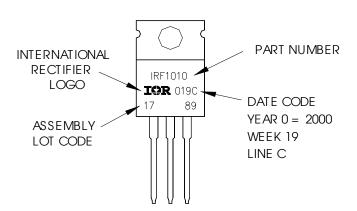
EXAMPLE: THIS IS AN IRF 1010

VIEW A-A

LOT CODE 1789

ASSEMBLED ON WW 19, 2000 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"

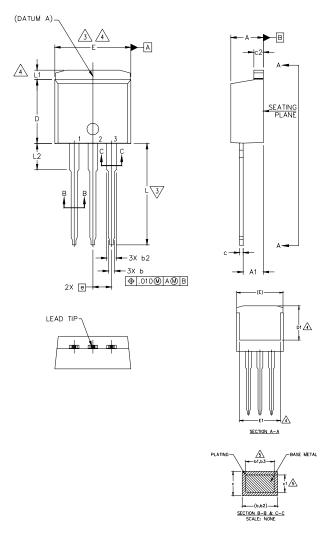


TO-220AB packages are not recommended for Surface Mount Application.

SECTION C-C & D-D

IRF1018E/S/SLPbF

TO-262 Package Outline (Dimensions are shown in millimeters (inches))



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.— OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(mox.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S Y		N			
M B O L	MILLIM	ETERS	INC	HES	NOTES
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	2.03	3.02	.080	.119	
b	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	_	4
Ε	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
е	2.54	BSC	.100 BSC		
L	13.46	14.10	.530	.555	
L1	-	1.65	-	.065	4
L2	3.56	3.71	.140	.146	

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE 2.- DRAIN

3.- SOURCE 4.- DRAIN

IGBTs, CoPACK

1.- GATE

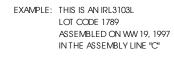
2.- COLLECTOR

3.- EMITTER

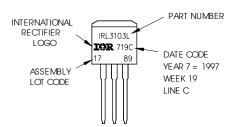
4. – COLLECTOR

TO-262 Part Marking Information

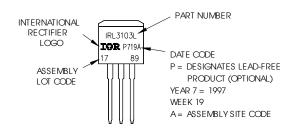
www.irf.com



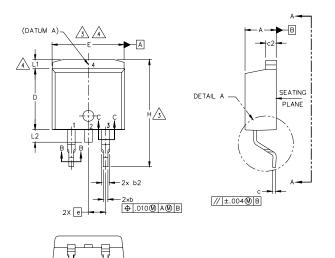
Note: "P" in assembly line position indicates "Lead — Free"



OR



D²Pak Package Outline (Dimensions are shown in millimeters (inches))



CAUCE PLANE 0'-8'	SEATING PLANE
(E) DETAIL "A" ROTATED 90' CW SCALE 8:1	
	PLATING (c) (b, b2) SECTION B-B & C-C SCALE: NONE

S Y			N		
M B O	MILLIM	ETERS	INC	HES	O T E S
l 0	MIN.	MAX.	MIN. MAX		E S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
e	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.65	-	.066	4
L2	1.27	1.78	-	.070	
L3	0.25	BSC	.010 BSC		1
L4	4.78	5.28	.188	.208	

LEAD ASSIGNMENTS

DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE) 2. 4. - CATHODE 3.- ANODE

HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

2, 4.- COLLECTOR 3.- EMITTER

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

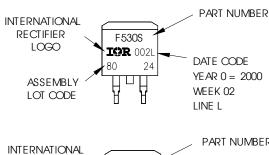
D²Pak Part Marking Information

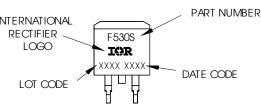
EXAMPLE: THIS IS AN IRF530S WITH

LOT CODE 8024

ASSEMBLED ON WW 02, 2000 IN THE ASSEMBLY LINE "L"

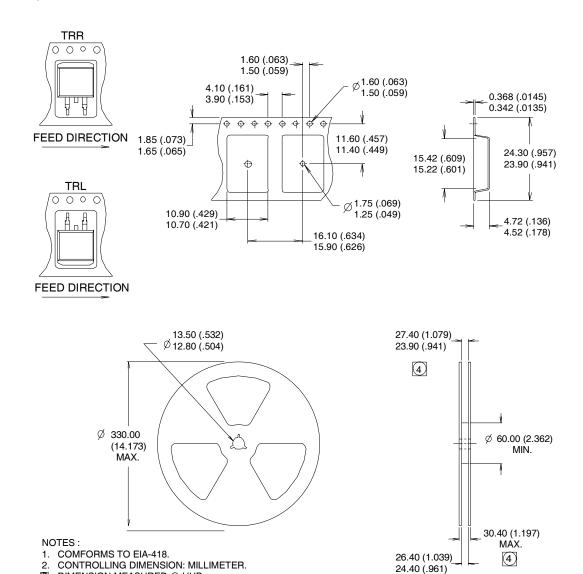
EXAMPLE: THIS IS AN IRF530S WITH For GB Production DE 8024 ASSEMBLED ON WW 02, 2000 IN THE ASSEMBLY LINE "L"





Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/

D²Pak Tape & Reel Information



Note: For the most current drawing please refer to IR website at: http://www.irf.com/package/

INCLUDES FLANGE DISTORTION @ OUTER EDGE.

DIMENSION MEASURED @ HUB.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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